Sea	rch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/711,790	LEE ET AL.
Examiner	Art Unit

2818

Dao H. Nguyen

SEARCHED				
Class	Subclass	Date	Examiner	
257	529,762	7/27/2007	DN	
	<u> </u>			
	<u> </u>			
			<u> </u>	
w				

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	history print	7/27/2007	DN

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT; USPG-PUB; EPO; JPO; IBM-TDB; USOCR) (See search history print out).	7/27/2007	DN
257/50,209,529,530,e21.592,e23.147-e23.15 (text search)	7/27/2007	DN
438/131,132,215,333,433,467,600,60 1 (text search)	7/27/2007	DN
H01L29/00,29/40	7/27/2007	DN